

- DEI-96-137 S.Yamanaka, H.Kawamura (Meijo University) K.Ito, J.Tomita (Showa Electrical Wire & Cable), T.Seguchi (Japan Atomic Energy Research Institute)
Life Evaluation of FR-CV Cable on Thermal-Radiation combined Aging by Micro-hardness
M.Sugiyama, A.Ogata, M.Nitta, T.Tani (Yazaki Electric Wire Co., Ltd)
T.Yagi, T.Seguchi (JAERI-Takasaki)
- DEI-96-138 Life-time Estimation of Cable Insulation Materials with Inorganic Flame-Retardants under the Radiation and Heat Environment
J.Ikehara, K.Kanemitsuya (Mitsubishi Cable Industry)
T.Yagi, Y.Morita, T.Seguchi (Takasaki Research Institute, JAERI)
- DEI-96-139 Mechanism of Degradation of Low-Voltage Cable aged by Thermal and Radiation.
T.Sato, Y.Kobayashi, S.Yoshida, T.Shiono (Showa Wire & Cable Co., Ltd.)
T.Taguchi, Y.Ichimori (Toshiba Corporation)
- DEI-96-140 Electrical and Mechanical Properties of Coaxial Cables for Use under High Temperature and Radiation Condition(3)
T.Seguchi, T.Yagi (Japan Atomic Energy Research Institute)
H.Mitsui, H.Masumoto (Toshiba Corp.)
T.Shiono, S.Ono, K.Oosada (Showa Electric Wire and Cable Co., Ltd.)
- DEI-96-141 Transient Excited-state Absorption Measurement in Ge-doped Silica Glass by a Pump-Probe Method
M.Fujimaki, S.K. Soo, Y.Ohki (Waseda University)
- DEI-96-142 Photoluminescence band at 700~900nm in High Purity Silica
Y.Sakurai, K.Nagasawa (Shonan Institute of Technology), H.Nishikawa (Tokyo Metropolitan University), Y.Ohki, Y.Hama (Waseda University)
- DEI-96-143 FT-IR Study of Ion-Implantation-Induced Damage of Thermal SiO₂ Films
H.Fukui, H.Nishikawa, E.Watanabe, D.Ito (Tokyo Metropolitan University)
M.Takiyama (Nippon Steel Corp.)
- DEI-96-144 Effects of fluorine addition on the structure and optical properties of SiO₂ films formed by plasma-enhanced chemical vapor deposition
K.Ishii, A.Takami, Y.Ohki (Waseda University)
- DEI-96-145 Observation of Generation and Drift of Carriers in Organic Photoconductor by Piezo-electrically Induced Pressure Wave Propagation Method
Y.Satoh, N.Adachi, Y.Tanaka, T.Takada (Musashi Institute of Technology)

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- DEI-97-2 100nm Ultra Fine Pattern Etching by a Polyimide Interface Transmitted Electron Beam Excited ICP
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- DEI-97-3 Characterization of Vanadyl-Phthalocyanine Thin Film Grown on KBr and Muscovite Substrates by Molecular Beam Epitaxy
L.Zhu, H.Takeda, S.Kawashima, H.Furuhashi, T.Yoshikawa, A.Maeda, S.Ochiai, Y.Uchida, K.Kojima, A.Ohashi, M.Ieda (Aichi Institute of Technology)
T.Mizutani (Nagoya University)
- DEI-97-4 Magnetic Orientation Effect on p-Phenylene Oligomer Thin Films Prepared by Vapor Deposition(I)
K.Mori, T.Mori, T.Mizutani (Nagoya University)
- DEI-97-5 Control of Molar Ratio and Molecular Orientation in TTF-TCNQ Charge-Transfer Complex Films and their Electrical Properties
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